

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>	Docket Number (Optional) TWI-24910	Application Number NEW
	Applicant(s) Alex Salnik et al.	
	Filing Date HEREWITH	Group Art Unit Unknown

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
MAL	*AA	4,579,463	04/01/1986	Rosencwaig et al.	374	57	05/21/1984
	*AB	4,634,290	01/06/1987	Rosencwaig et al.	374	5	11/14/1985
	*AC	4,636,088	01/13/1987	Rosencwaig et al.	374	5	05/21/1984
	*AD	5,978,074	11/02/1999	Opsal et al.	356	72	07/03/1997
	*AE	6,049,220	04/11/2000	Borden et al.	324	765	06/10/1998
	*AF	6,323,951	11/27/2001	Borden et al.	356	502	03/22/1999
MAL	*AG	US 2002/0167326	11/14/2002	Borden et al.	327	752	03/05/2001

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

MAL	AH	J. Opsal et al., "Theory of the Temporal Behavior of Modulated Optical Reflectance in Silicon," <i>Digest of 5th International Topical Meeting of Photoacoustic and Photothermal Phenomena (Heidelberg, Germany)</i> , July 27-30, 1987, pp. coversheet, 103-104.
	AI	J. Opsal et al., "Temporal behavior of modulated optical reflectance in silicon," <i>J. Appl. Phys.</i> , Vol. 61, No. 1, 1 January 1987, pp. 240-248.
	AJ	A. Rosencwaig et al., "Temporal Behavior of Modulated Reflectance Signal in Silicon," from Review of Progress in Quantitative Nondestructive Evaluation, <i>Rev. Progress in QNDE</i> , Vol. 6A (1987), pp. 237-244.
	AK	A. Rosencwaig et al., "Temporal Behavior of Modulated Optical Reflectance in Silicon," Abstract submitted for the March 1986 Meeting of the American Physical Society March 31-April 4, 1986, <i>Bulletin of the American Physical Society</i> 31(3), March 1986, p. 633.
	AL	Excerpt: Therman-Probe 420 User Manual; Theory of Operation; Damage Relaxation (Decay Factor), 1 page in length. [See p. 3 of this Information Disclosure Statement for explanation]
MAL	AM	In re U.S. Patent Application No. 10/387,259, filed March 12, 2003, entitled "Ion Implant Monitoring Through Measurement of Modulated Optical Response," by Alex Salnik et al., 17 pages in length.

Examiner /Michael A. Lyons/	Date Considered 05/18/2006
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	